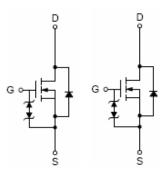
: :

Features

- $V_{DSS}=100V/V_{GSS}=\pm 20V/I_{D}=3.5A$
- $R_{RS(ON)} = 105 \text{m}\Omega(\text{Max.}) @V_{GS} = 10V$
- . $R_{DS(ON)} = 1.75 m \Omega(Max.) @V_{GS} = 4.5 V$
- ESD protect
- Reliable and Rugged
- High Density Cell Design For Ultra Low On-Resistance

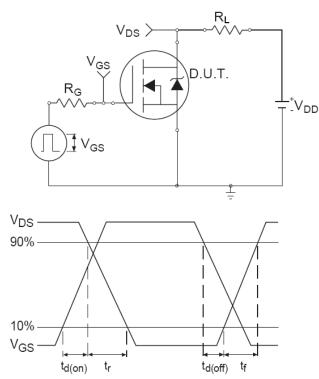
Pin Description



. Applications

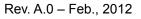
- •• "Synchronous Rectification
- Power Management in Inverter System

Switching Time Test Circuit and Waveforms



Package Marking and Ordering Information

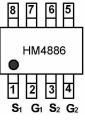
Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM4886	HM4886E	SOP-8	-	-	-







Marking and pin Assignment





SOP-8 top view

Parameter Symbol Typical Unit V_{DSS} Drain-Source Voltage 100 V Gate -Source Voltage ±20 V V_{GSS} $T_C = 70^{\circ}C$ 2.8 A I_D^{-1} Continuous Drain Current 3.5 А 300us Pulsed Drain Current Tested $T_C=25^{\circ}C$ 14 A I_{DM}¹ I_{S}^{1} **Diode Continuous Forward Current** 3 A Avalanche Energy, Single Plused(L=0.3mH) E_{AS}^2 30 mJ °C **Operating Junction Temperature** 150 T_J Storage Temperature Range $-55 \sim 150$ °C T_{STG}

Absolute Maximum Ratings (T_A=25°C unless otherwise noted)

Note: 1: Surface Mounted on $1in^2$ pad area, $t \leq 10$ sec..

2: UIS tested and pluse width limited by maximum junction temperature 150° C (initial temperature T_J= 25° C).

Electrical Characteristics (TA=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур	Max.	Unit
Static Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V,I _D =250uA	100			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-80V,V _{GS} =0V			1	uA
	Zero Gate voltage Drain Current	T _J =85°C			30	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} ,I _D =-250uA	1.5	2	2.5	V
I _{GSS}	Gate Leakage Current	V_{GS} =±16V, V_{DS} =0V			±10	nA
$R_{DS(on)}^{1}$	Drain-Source On-Resistance	V _{GS} =10V, I _D =3.5A		85	105	mΩ
	Drain-Source On-Resistance	V _{GS} =4.5V, I _D =2A		135	175	
Diode Chai	racteristics					
V_{SD}^{1}	Diode Forward Voltage	$I_{SD}=3A, V_{GS}=0V$	0.6	0.8	1.1	V
t _{rr}	Reverse Recovery Time	I _{SD} =3.5A,		44		ns
Qrr	Reverse Recovery Charge	dI _{SD} /dt=100A/us		80		nC
Dynamic C	haracteristics ²					
C _{iss}	Input Capacitance	V = 0 V V = 20 V		940		pF
C _{oss}	Output Capacitance	V _{GS} =0V, V _{DS} =30V Frequency=1MHz		80		
C _{rss}	Reverse Transfer Capacitance	riequency-invitiz		50		
t _{d(on)}	Turn-On Delay Time	V = 20 V D = 200		13	24	- ns
t _r	Turn-On Rise Time	V_{DD} =30V, R_L =30 Ω I_D =1A, V_{GEN} =10V		10	19	
t _{d(off)}	Turn-Off Delay Time	$R_{G}=6\Omega$		32	60	
t _f	Turn-Off Fall Time	NG-022		16	30	
Gate Charg	ge Characteristics ²					
Qg	Total Gate Charge	V = 50 V V = 10 V		21		nC
Q _{gs}	Gate-Source Charge	V_{DS} =50V, V_{GS} =10V I_D =3.5A		4.9		
Q _{gd}	Gate-Drain Charge	1D-3.3A		5.8		

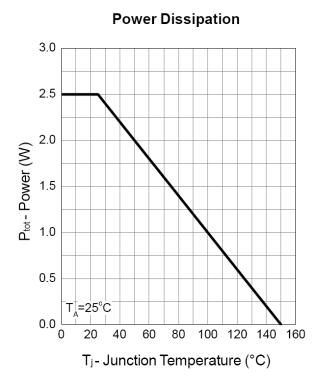
Note: 1: Pulse test ; pulse width \leq 300ns, duty cycle \leq 2%.

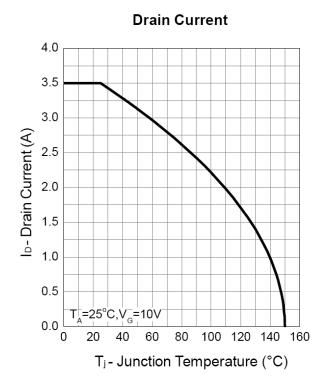
2: Guaranteed by design, not subject to production testing.

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HM4886E 100V_{DS}/±20V_{GS}/3.5A(I_D) Dual N-Channel Enha ncement Mode MOSFET

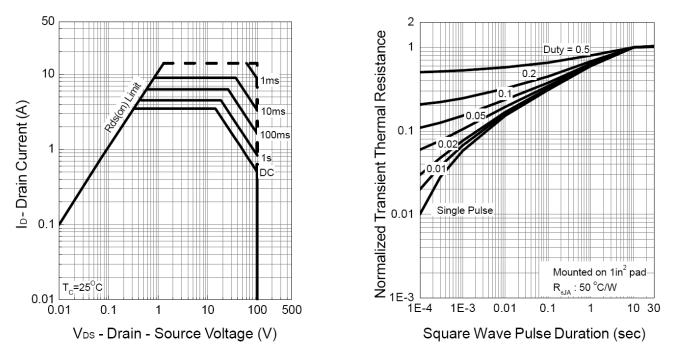
Typical Characteristics





Safe Operation Area

Thermal Transient Impedance

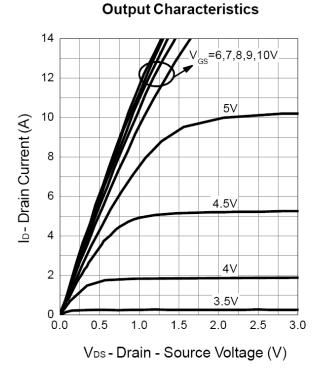


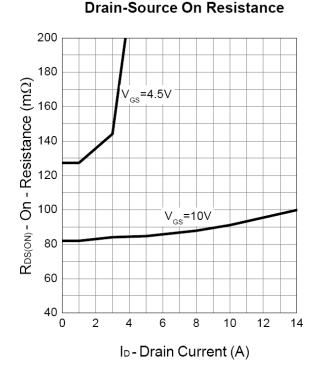
Rev. A.0 - Feb., 2012

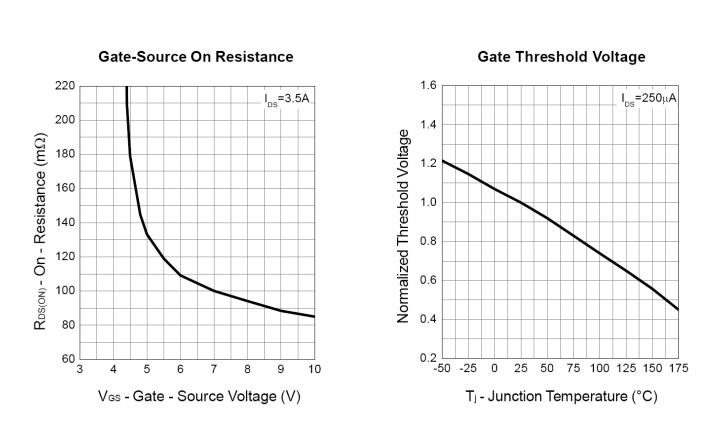
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HM4886E 100V_{DS}/±20V_{GS}/3.5A(I_D) Dual N-Channel Enha ncement Mode MOSFET

Typical Characteristics (Cont.)





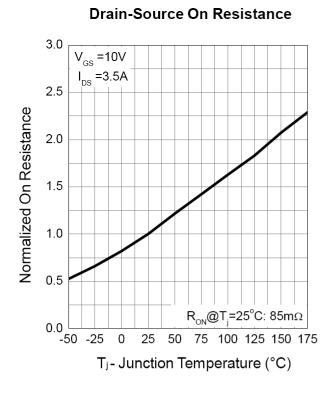


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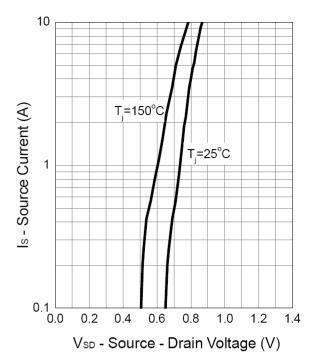
HM4886E 100V_{DS}/±20V_{GS}/3.5A(I_D) Dual N-Channel Enha ncement Mode MOSFET

Typical Characteristics (Cont.)

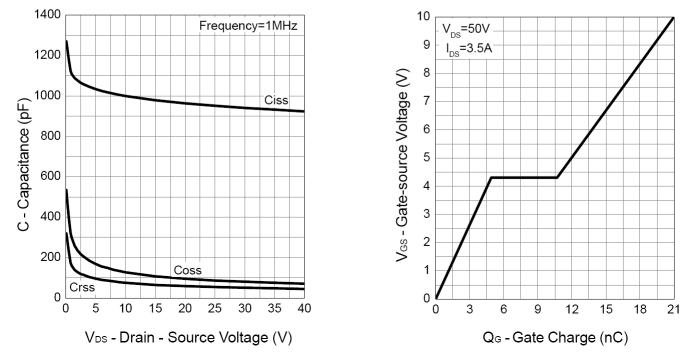


Capacitance

Source-Drain Diode Forward

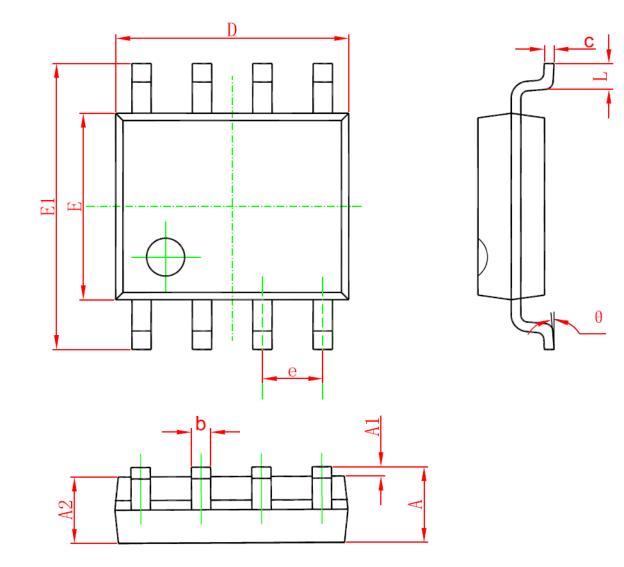






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Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
А	1.350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0.004	0.010	
A2	1.350	1.550	0.053	0. 061	
b	0. 330	0. 510	0.013	0. 020	
с	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
E	3.800	4.000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1.270	0.016	0. 050	
θ	0°	8°	0°	8°	

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